

CHANGE NOTIFICATION



Linear Technology Corporation
1630 McCarthy Blvd., Milpitas, CA 95035-7417
(408) 432-1900

October 7, 2015

Dear Sir/Madam:

PCN#100715

Subject: Notification of Change to LTM2987 Die

Please be advised that Linear Technology Corporation has made a minor change to the LTM2987 die. This silicon change improves the startup behavior of the bandgap reference. Under a narrow set of conditions, the bandgap reference might stall at ~0.7V and remain there for an extended period of time, but eventually recovering. A M1-via-M2 mask edit eliminates the problem. An additional edit was made to improve the wafer sort yield to the V_{OUT_ENn} and V_{IN_EN} Output High Voltage specifications. This change modified the NWELL layer and added an additional NWELL mask step. No changes to the EC table specification were made.

Product specifications are unaffected and the datasheet remains unchanged. The die change was qualified by performing characterization over the full operating junction temperature range and through rigorous engineering evaluation across a broad range of application conditions. In addition, the product successfully completed 500 hours of HTOL stress testing. Samples of the revised die are available now upon request. Product built using the improved design is targeted for shipment around early January 2016.

Should you have any further questions or concerns please contact your local Linear Technology Sales person or you may contact me at 408-432-1900 ext. 2077, or by e-mail at JASON.HU@LINEAR.COM. If I do not hear from you by December 07, 2015, we will consider this change to be approved by your company.

Sincerely,

Jason Hu

Quality Assurance Engineer